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CNC	AA	2,810,324	10/1957	Marks					
cul	AB	3,912,920	10/1975	Kubota					
cu	AC	5,889,571	03/1999	Kim et al.					
all	AD	5,909,265	06/1999	Kim et al.					
all	AE	5,982,466	11/1999	Choi et al.					
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one	AF	3-120503	05/1991	Japan					
one one one	AG	3-241311	10/1991	Japan					
cu	АН	5-19209	01/1993	Japan					
au	Al	7-318861	12/1995	Japan					
cue	AJ	10-90684	01/1998	Japan					
cue	AK	10-161126	06/1998	Japan					
one	AL	10-154658	06/1998	Japan					
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ene	AN	11-194344	07/1999	Japan					
cu	AO	11-194345	07/1999	Japan					
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an	АР	Hecht, "Optics," Addiso	n-Wesley Publish	ing co., 2 <sup>nd</sup> Edition, pp:298-99.					
cue	AQ	Jenkins, Francis A., Harv	rey E. White, Fun	damentals of Optics 3rd edition, pp: 492-3.					
AR M. Nam et al., "Wide-Viewing-Angle TFT-LCD with Photo-Aligned Four-Domain TN Mode," SID 97 Digest, pp: 933-6.									
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au	AA	5,657,105	08/1997	McCartney					
au	AB	5,712,696	01/1998	Toko et al.					
cuc	AC	5,764,326	06/1998	Hasegawa et al.					
au	AD	5,767,994	08/1993	Kang et al.				_	
all	AE	5,784,139	07/1998	Chigrinov et al.					
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all	AF	4-7520	01/1992	Japan					
ow	AG	4-284421	10/1992	Japan					
ou	АН	4-350822	12/1992	Japan					
all	Al	5-34699	02/1993	Japan					
cul	AJ	5-53513	03/1993	Japan					
all	AK	5-232473	09/1993	Japan					
(NV	AL	7-261185	10/1995	Japan					
an	AM	0 525 473	02/1993	EPO					
all	AR	0 525 478	02/1993	EPO					
cu	AO	0 611 786	07/1996	EPO					
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cul	AP	D. Seo et al., "Invited A	ddress: Surface	Alignment of Liquid Crystals in LCDs," SID	93 Digest, pp:	954-6.			
cne	AQ	Y. limura, "Invited Addr	ess: Prospects o	of the Photo-Alignment Technique for LCD	Fabrication," (	SID 97 Digest, pp: 3	11-4.		
cu	AR	R. Shashidhar et al., "A	New Non-Rubbii	ng Technique for Liquid-Crystal Alignment,	" SID 97 Diges	t, pp: 315-8.			
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au	AA	5,539,074	07/1996	Herr et al.						
M	AB	5,576,862	11/1996	Sugiyama et al.						
m	AC	5,578,351	11/1996	Shashidhar et al.						
M	AD	5,602,661	02/1997	Schadt et al.						
M	AE	5,604,615	02/1997	lwagoe et al.						
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all	AF	0 708 354	07/1996	EPO						
un	AG	0 742 471	●7/1996	EPO						
cul	АН	0 750 212	12/1996	EPO						
W	Al	44 20 585	12/1996	Germany						
all	AJ	64-60833	03/1989	Japan						
w	AK	1-251344	10/1989	Japan						
cu	AL	1-251345	10/1989	Japan						
au	АМ	0 635 748	01/1995	EPO						
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au	АР	K. Lee et al., "Late-New Digest, pp: 638-41.	s Poster: Mecha	nism of UV Modification of LC Pretilt Angle	and Its Applic	cation to Two-Dom	ain TN-LCDs,'	'SID 96		
one	AR	J. Kim et al., "Late News	S Poster: Photo-	Alignment of Liquid Crystals Using a New P	hotopolymer,	" SID 96 Digest, pp	: 646-9.			
cu	AR	Y. Saitoh et al., "Stability of UV-Type Two-Domain Wide-Viewing Angle TFT-LCD Panels," SID 96 Digest, pp: 662-5.								
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au	AC	5,464,669	11/1995	Kang et al.					
Cuc	AD	5,479,282	12/1995	Toko et al.					
m	AE	5,538,823	07/19196	Park et al.					
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au	AQ	H. Soh et al., "The Reali	zation of Wide V	riewing Angle	TFT-LCDs Using Photo-Align	ment Method,	" Euro Display 96,	pp: 579-82.	
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all	AA	4,974,941	12/1990	Gibbons et al.				
W	AB	5,032,009	07/1991	Gibbons et al.				
cul	AC	5,073,294	12/1991	Shannon et al.				
an	AD	5,296,321	03/1994	Kawanishi et al.				
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all	AP	A. Lien, <i>UV-Type Two-D</i>	omain Wide Vie	wing Angle TFT/LCD Panels," Asia Display 9	5, <b>pp: 593-6</b> .			
AQ T. Yamamoto, Liquid-Crystal Alignment by Slantwise Irradiation of Non-Polarized UV Light on a Polylmide Layer," SID 96 Digest, pp.						p: 642-5.		
IM	AR	M. Schadt et al., "Optical patterning of multi-domain liquid-crystal displays with wide viewing angles," Letters to Nature, Vol. 381, 05/16/96.						
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all	AP	J. West et al., "Polarized	d UV-Exposed Pe	olyimide Films for Liquid-Cry	rstal Alignment,	" SID 95 Dige	st, pp: 703-5.				
all	AQ	T. Hashimoto et al., "TN- 877-80.	LCD with Quarte	ered Subpixels Using Polariz	ed UV-Light-Irr	adiated Polyn	ner Orientation File	ms," SID 95 Dig	gest, pp:		
M	AR	T. Saitoh et al., "A New I	Saitch et al., "A New Hybrid N-TB Mode LCD with Two Domain Pixels Fabricated Using a Photopolymer," Asia Display, pp. 589-92.								
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all	AQ		Hasegawa, "Nematic Homogeneous Photo Alignment by Polyimide Exposure to Linearly Polarized UV," Journal of Photopolymer Science d Technology, Vol. 8, No. 2, 1995, pp: 241-8.								
au	AR		M. Schadt, "Investigation of the Mechanism of the Surface-Induced Alignment of Liquid Crystals by Linearly Polymerized Photopolymers," SID 95 Digest, pp: 528-31.								
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al	AQ	Y. limura et al., "Invited Method," SID 94 Digest		o-Optic Characteristics of Amorphous and S	Super-Multido	main TN-LCDs Pre	pared by a No	n-Rubbing			
all	AR	M. Schadt et al., "Photo-Generation of Linearly Polymerized Liquid Crystal Aligning Layers Comprising Novel, Integrated Optically Patterned Retarders and Color Filters," Jpn. J. Appl. Phys. Vol. 34 (1995), pp: 3240-9, Part 1, No. 6A, June 1995.									
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cue	AQ	T. Marushii et al., "Photo	sensitive Orien	tants for Liquid Crystal Alignment,," Mol. Ma	at. 1993, Vol. 3	, pp: 161-8.					
ul	AR  Y. Toko et al., "TN-LCDs Fabricated by Non-Rubbing Showing Wide and Homogeneous Viewing Angular Characteristics and Excellent Voltage Holding Ratio," SID 93 Digest, pp. 622-5.										
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\*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Praw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\*\*English-language abstract provided.